











#### TLV316-Q1, TLV2316-Q1, TLV4316-Q1

SBOS845A - NOVEMBER 2016-REVISED DECEMBER 2016

## TLVx316-Q1

# 10-MHz, Rail-to-Rail Input/Output, Low-Voltage, 1.8-V CMOS Operational Amplifiers

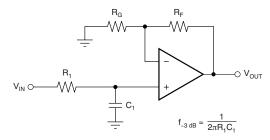
#### **Features**

- **Qualified for Automotive Applications**
- AEC-Q100 With the Following Results:
  - Device Temperature Grade 1: -40°C to +125°C Ambient Operating Temperature Range
  - Device HBM ESD Classification Level 3A
  - Device CDM ESD Classification Level C5
- Unity-Gain Bandwidth: 10 MHz
- Low Io: 400 µA/ch
  - Excellent Power-to-Bandwidth Ratio
  - Stable I<sub>O</sub> Overtemperature and Supply Range
- Wide Supply Range: 1.8 V to 5.5 V
- Low Noise: 12 nV/√Hz at 1 kHz
- Low Input Bias Current: ±10 pA
- Offset Voltage: ±0.75 mV
- **Unity-Gain Stable**
- Internal RFI and EMI Filter
- Number of Channels:
  - TLV314-Q1: 1
  - TLV2314-Q1: 2
  - TLV4314-Q1: 4
- Extended Temperature Range: -40°C to +125°C

### Applications

- Automotive Applications:
  - ADAS
  - Body Electronics and Lighting
  - **Current Sensing**
  - **Battery Management Systems**

#### Single-Pole, Low-Pass Filter



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

## 3 Description

The TLV316-Q1 (single), TLV2316-Q1 (dual), and TLV4316-Q1 (quad) devices comprise a family of general-purpose, low-power operational amplifiers. Features such as rail-to-rail input and output swings, low quiescent current (400 µA/ch typical) combined with a wide bandwidth of 10 MHz, and very-low noise (12 nV/√Hz at 1 kHz) make this family suitable for a circuits requiring a good speed and power ratio. The low input bias current supports operational amplifiers that are used in applications with megaohm source impedances. The low-input bias current of the TLVx316-Q1 yields a very-low current noise to make the family attractive for high impedance sensor interfaces.

The robust design of the TLVx316-Q1 provides easeof-use to the circuit designer: a unity-gain stable, integrated RFI and EMI rejection filter, no phase reversal in overdrive condition, and high electrostatic discharge (ESD) protection (4-kV HBM).

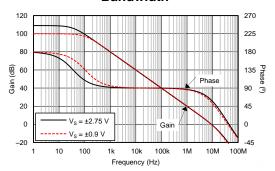
These devices are optimized for low-voltage operation as low as 1.8 V (±0.9 V) and up to 5.5 V (±2.75 V). This latest addition of low-voltage CMOS operational amplifiers to the portfolio, in conjunction with the TLVx313-Q1 and TLVx314-Q1 series, offer a family of bandwidth, noise, and power options to meet the needs of a wide variety of applications.

#### Device Information<sup>(1)</sup>

PART NUMBER	PACKAGE	BODY SIZE (NOM)
TLV316-Q1	SOT-23 (5)	1.60 mm × 2.90 mm
TLV2316-Q1	VSSOP (8)	3.00 mm × 3.00 mm
TLV4316-Q1	TSSOP (14)	4.40 mm × 5.00 mm

(1) For all available packages, see the orderable addendum at the end of the data sheet.

### Low Supply Current (400 µA/Ch) for 10-MHz Bandwidth





## **Table of Contents**

1	Features 1	7.3 Feature Description14
2	Applications 1	7.4 Device Functional Modes15
3	Description 1	8 Application and Implementation 16
4	Revision History 2	8.1 Application Information
5	Pin Configuration and Functions	8.2 System Examples
6	Specifications6	9 Power Supply Recommendations 17
•	6.1 Absolute Maximum Ratings	9.1 Input and ESD Protection
	6.2 ESD Ratings	10 Layout 18
	6.3 Recommended Operating Conditions	10.1 Layout Guidelines
	6.4 Thermal Information: TLV316-Q1	10.2 Layout Example 18
	6.5 Thermal Information: TLV2316-Q17	11 Device and Documentation Support 19
	6.6 Thermal Information: TLV4316-Q1	11.1 Documentation Support
	6.7 Electrical Characteristics	11.2 Related Links
	6.8 Typical Characteristics: Table of Graphs9	11.3 Community Resources
	6.9 Typical Characteristics	11.4 Trademarks19
7	Detailed Description 13	11.5 Electrostatic Discharge Caution
-	7.1 Overview	11.6 Glossary
	7.2 Functional Block Diagram	12 Mechanical, Packaging, and Orderable Information20

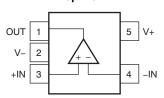
## 4 Revision History

CI	hanges from Original (November 2016) to Revision A	Page
•	Changed the CDM ESD Classification Level from C6 to C5 in the Features section	1
•	Deleted the SC70 (5), SOIC (8), and SOIC (14) packages from the Device Information table	1
•	Deleted the DCK (SC70) package from the TLV316-Q1 pinout diagram in the <i>Pin Configurations and Functions</i> section	3
•	Deleted the DCK (SC70) pinout information from the <i>Pin Functions: TLV316-Q1</i> table in the <i>Pin Configurations and Functions</i> section	
•	Deleted D (SOIC) package from the TLV2316-Q1 pinout diagram in the Pin Configurations and Functions section	4
•	Deleted the D (SOIC) package from TLV4316-Q1 pinout diagram in the Pin Configurations and Functions section	5
•	Changed the ESD Ratings table from commercial to automotive specifications	6
•	Changed the CDM ESD rating from ±1500 to ±750 in the ESD Ratings table	6
•	Deleted the DCK (SC70) package from the Thermal Information: TLV316-Q1 table in the Specifications section	<mark>7</mark>
•	Changed the formatting of all <i>Thermal Information</i> table notes	<mark>7</mark>
•	Deleted the D (SOIC) package from the Thermal Information: TLV2316-Q1 table in the Specifications section	<mark>7</mark>
•	Deleted the D (SOIC) package from the Thermal Information: TLV4316-Q1 table in the Specifications section	<mark>7</mark>
•	Deleted the static literature number in the SBOA128 application note reference in the <i>EMI Susceptibility and Input Filtering</i> section	15
•	Deleted the static literature number in document reference in the Layout Guidelines section	18
•	Changed the layout example image (Figure 41) in Layout Example section	18



## 5 Pin Configuration and Functions

#### TLV316-Q1 DBV Package 5-Pin SOT-23 Top View



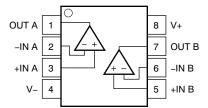
### Pin Functions: TLV316-Q1

PIN		1/0	DESCRIPTION	
NAME	NO.	I/O	DESCRIPTION	
-IN	4	I	Inverting input	
+IN	3	I	Noninverting input	
OUT	1	0	Dutput	
V-	2	_	legative (lowest) supply or ground (for single-supply operation)	
V+	5	_	Positive (highest) supply	

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#### TLV2316-Q1 DGK Package 8-Pin VSSOP Top View

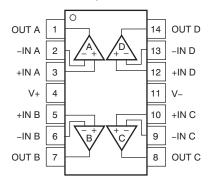


### Pin Functions: TLV2316 -Q1

PIN		1/0	DECORIDATION	
NAME	NO.	1/0	DESCRIPTION	
–IN A	2	1	Inverting input, channel A	
+IN A	3	- 1	Noninverting input, channel A	
–IN B	6	1	nverting input, channel B	
+IN B	5	1	Noninverting input, channel B	
OUT A	1	0	Dutput, channel A	
OUT B	7	0	Output, channel B	
V-	4	_	Negative (lowest) supply or ground (for single-supply operation)	
V+	8	_	Positive (highest) supply	



#### TLV4316-Q1 PW Package 14-Pin TSSOP Top View



### Pin Functions: TLV4316-Q1

PIN		1/0	DESCRIPTION	
NAME	NO.	1/0	DESCRIPTION	
–IN A	2	I	Inverting input, channel A	
+IN A	3	I	Noninverting input, channel A	
–IN B	6	I	Inverting input, channel B	
+IN B	5	I	Noninverting input, channel B	
–IN C	9	I	Inverting input, channel C	
+IN C	10	ı	Noninverting input, channel C	
–IN D	13	ı	Inverting input, channel D	
+IN D	12	I	Noninverting input, channel D	
OUT A	1	0	Output, channel A	
OUT B	7	0	Output, channel B	
OUT C	8	0	Output, channel C	
OUT D	14	0	Output, channel D	
V-	11	_	Negative (lowest) supply or ground (for single-supply operation)	
V+	4	_	Positive (highest) supply	



## 6 Specifications

## 6.1 Absolute Maximum Ratings

over operating free-air temperature (unless otherwise noted)<sup>(1)</sup>

			MIN	MAX	UNIT	
Supply voltage				7	V	
	Voltage <sup>(2)</sup>	Common-mode	(V-) - 0.5	(V+) + 0.5	.,	
Signal input pins	voltage (=)	Differential		(V+) - (V-) + 0.2	V	
	Current <sup>(2)</sup>	·	-10	10	mA	
Output short-circu	uit <sup>(3)</sup>		Cont	tinuous		
	Specified, T <sub>A</sub>		-40	125		
Temperature	Junction, T <sub>J</sub>			150	°C	
	Storage, T <sub>stg</sub>		-65	150		

<sup>(1)</sup> Stresses beyond those listed under Absolute Maximum Ratings may cause permanent damage to the device. These are stress ratings only, and functional operation of the device at these or any other conditions beyond those indicated under Recommended Operating Conditions is not implied. Exposure to absolute-maximum-rated conditions for extended periods may affect device reliability.

## 6.2 ESD Ratings

			VALUE	UNIT
V <sub>(ESD)</sub> Electrostatic d	Electrost d'es l'este en e	Human-body model (HBM), per AEC Q100-002 <sup>(1)</sup>	±4000	.,
	Electrostatic discharge	Charged-device model (CDM), per AEC Q100-011	±750	V

<sup>(1)</sup> AEC Q100-002 indicates that HBM stressing shall be in accordance with the ANSI/ESDA/JEDEC JS-001 specification.

### 6.3 Recommended Operating Conditions

over operating free-air temperature range (unless otherwise noted)

		MIN	NOM MAX	UNIT
$V_S$	Supply voltage	1.8	5.5	V
	Specified temperature range	-40	125	°C

<sup>(2)</sup> Input pins are diode-clamped to the power-supply rails. Current limit input signals that can swing more than 0.5 V beyond the supply rails to 10 mA or less.

<sup>(3)</sup> Short-circuit to ground, one amplifier per package.



#### 6.4 Thermal Information: TLV316-Q1

		TLV316-Q1	
	THERMAL METRIC <sup>(1)</sup>	DBV (SOT-23)	UNIT
		5 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	221.7	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	144.7	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	49.7	°C/W
ΨЈΤ	Junction-to-top characterization parameter	26.1	°C/W
ΨЈВ	Junction-to-board characterization parameter	49.0	°C/W
R <sub>0</sub> JC(bot)	Junction-to-case(bottom) thermal resistance	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

## 6.5 Thermal Information: TLV2316-Q1

		TLV2316-Q1	
	THERMAL METRIC <sup>(1)</sup>	DGK (VSSOP)	UNIT
		8 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	186.6	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	78.8	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	107.9	°C/W
ΨЈТ	Junction-to-top characterization parameter	15.5	°C/W
ΨЈВ	Junction-to-board characterization parameter	106.3	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

#### 6.6 Thermal Information: TLV4316-Q1

		TLV4316-Q1	
	THERMAL METRIC <sup>(1)</sup>	PW (TSSOP)	UNIT
		14 PINS	
$R_{\theta JA}$	Junction-to-ambient thermal resistance	117.2	°C/W
$R_{\theta JC(top)}$	Junction-to-case(top) thermal resistance	46.2	°C/W
$R_{\theta JB}$	Junction-to-board thermal resistance	58.9	°C/W
ΨЈТ	Junction-to-top characterization parameter	4.9	°C/W
ΨЈВ	Junction-to-board characterization parameter	58.3	°C/W
$R_{\theta JC(bot)}$	Junction-to-case(bottom) thermal resistance	N/A	°C/W

 For more information about traditional and new thermal metrics, see the Semiconductor and IC Package Thermal Metrics application report.

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## 6.7 Electrical Characteristics

at  $T_A = 25^{\circ}C$ ,  $R_L = 10 \text{ k}\Omega$  connected to  $V_S$  / 2,  $V_{CM} = V_S$  / 2, and  $V_{OUT} = V_S$  / 2 (unless otherwise noted);  $V_S$  (total supply voltage) = (V+) - (V-) = 1.8 V to 5.5 V

	PARAMETER	TEST CONDITIONS	MIN	TYP	MAX	UNIT		
OFFSET	VOLTAGE							
		V <sub>S</sub> = 5 V		±0.75	±3			
Vos	Input offset voltage	V <sub>S</sub> = 5 V, T <sub>A</sub> = -40°C to 125°C			±4.5	mV		
dV <sub>OS</sub> /dT	Drift	V <sub>S</sub> = 5 V, T <sub>A</sub> = -40°C to 125°C		±2		μV/°C		
PSRR	Power-supply rejection ratio	$V_S = 1.8 \text{ V} - 5.5 \text{ V}, V_{CM} = (V-)$		±30	±175	μV/V		
	Channel separation, dc	At dc		100		dB		
INPUT V	OLTAGE RANGE	1	"					
V <sub>CM</sub>	Common-mode voltage range	V <sub>S</sub> = 5.5 V	(V-) - 0.2		(V+) + 0.2	V		
OMPR		$V_S = 5.5 \text{ V}, (V-) - 0.2 \text{ V} < V_{CM} < (V+) - 1.4 \text{ V},$ $T_A = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$		15				
CMRR	Common-mode rejection ratio	$V_S = 5.5 \text{ V}, V_{CM} = -0.2 \text{ V to } 5.7 \text{ V}, \\ T_A = -40 ^{\circ}\text{C to } 125 ^{\circ}\text{C}$		75		dB		
INPUT BI	AS CURRENT							
I <sub>B</sub>	Input bias current			±10		pA		
Ios	Input offset current			±10		pA		
NOISE								
En	Input voltage noise (peak-to-peak)	V <sub>S</sub> = 5 V, f = 0.1 Hz to 10 Hz		5		$\mu V_{PP}$		
e <sub>n</sub>	Input voltage noise density	V <sub>S</sub> = 5 V, f = 1 kHz		12		nV/√ <del>Hz</del>		
i <sub>n</sub>	Input current noise density	f = 1 kHz		1.3		fA/√ <del>Hz</del>		
INPUT IM	IPEDANCE							
Z <sub>ID</sub>	Differential			2    2		10 <sup>16</sup> Ω    pF		
Z <sub>IC</sub>	Common-mode			2    4		10 <sup>11</sup> Ω    pF		
OPEN-LC	OOP GAIN							
٨	Open leep veltage gain	$\begin{aligned} V_S &= 5.5 \text{ V, } (V-) + 0.05 \text{ V} < V_O < (V+) - 0.05 \text{ V,} \\ R_L &= 10 \text{ k}\Omega \end{aligned}$		104		dР		
A <sub>OL</sub>	Open-loop voltage gain	$V_S = 5.5 \text{ V}, (V-) + 0.15 \text{ V} < V_O < (V+) - 0.15 \text{ V}, \\ R_L = 2 \text{ k}\Omega$		104		dB		
FREQUE	NCY RESPONSE							
GBP	Gain bandwidth product	V <sub>S</sub> = 5 V, G = 1		10		MHz		
$\phi_{\text{m}}$	Phase margin	V <sub>S</sub> = 5 V, G = 1		60		Degrees		
SR	Slew rate	V <sub>S</sub> = 5 V, G = 1		6		V/μs		
t <sub>S</sub>	Settling time	To 0.1%, $V_S = 5 \text{ V}$ , 2-V step , $G = 1$ , $C_L = 100 \text{ pF}$		1		μS		
t <sub>OR</sub>	Overload recovery time	$V_S = 5 \text{ V}, V_{IN} \times \text{gain} = V_S$		0.8		μS		
THD + N	Total harmonic distortion + noise <sup>(1)</sup>	$V_S = 5 \text{ V}, V_O = 0.5 \text{ V}_{RMS}, G = 1, f = 1 \text{ kHz}$	0	.008%				
OUTPUT								
Vo	Voltage output swing from supply	$V_S = 1.8 \text{ V to } 5.5 \text{ V}, R_L = 10 \text{ k}\Omega$			35	m\/		
v <sub>O</sub>	rails	$V_S = 1.8$ to 5.5 V, $R_L = 2$ k $\Omega$			125	mV		
I <sub>SC</sub>	Short-circuit current	V <sub>S</sub> = 5 V		±50		mA		
Z <sub>O</sub>	Open-loop output impedance	V <sub>S</sub> = 5 V, f = 10 MHz		250		Ω		
POWER :	SUPPLY							
Vs	Specified voltage range		1.8		5.5	V		
IQ	Quiescent current per amplifier	$V_S = 5 \text{ V}, I_O = 0 \text{ mA}, T_A = -40^{\circ}\text{C} \text{ to } 125^{\circ}\text{C}$		400	575	μΑ		
TEMPER	ATURE							
T <sub>A</sub>	Specified		-40		125	°C		
T <sub>stg</sub>	Storage		-65		150	°C		

<sup>(1)</sup> Third-order filter; bandwidth = 80 kHz at -3 dB.

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## 6.8 Typical Characteristics: Table of Graphs

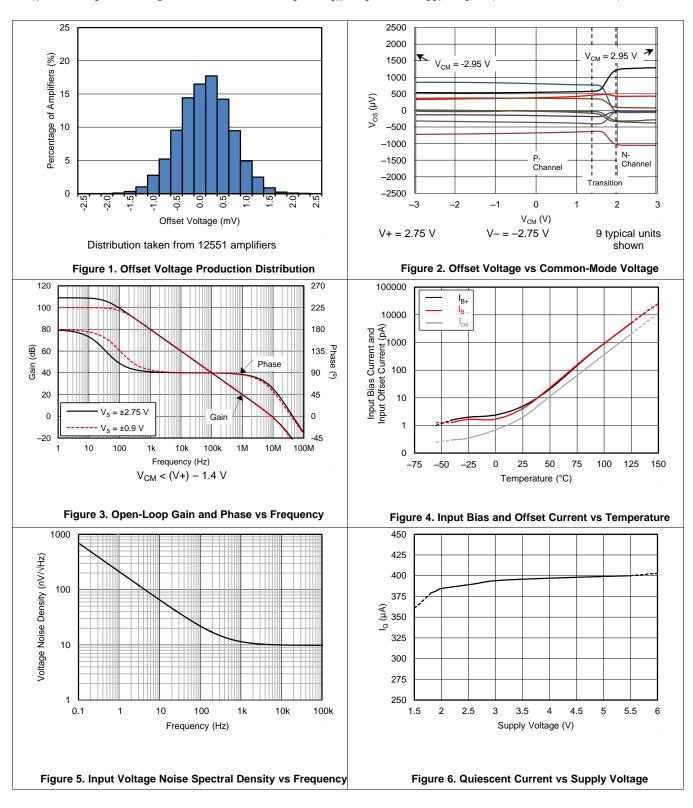
## Table 1. Table of Graphs

TITLE	FIGURE
Offset Voltage Production Distribution	Figure 1
Offset Voltage vs Common-Mode Voltage	Figure 2
Open- Loop Gain and Phase vs Frequency	Figure 3
Input Bias and Offset Current vs Temperature	Figure 4
Input Voltage Noise Spectral Density vs Frequency	Figure 5
Quiescent Current vs Supply Voltage	Figure 6
Small-Signal Overshoot vs Load Capacitance	Figure 7
No Phase Reversal	Figure 8
Small-Signal Step Response	Figure 9
Large-Signal Step Response	Figure 10
Short-Circuit Current vs Temperature	Figure 11
Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency	Figure 12
Channel Separation vs Frequency	Figure 13

# TEXAS INSTRUMENTS

### 6.9 Typical Characteristics

at  $T_A = 25$  °C,  $V_S = 5.5$  V,  $R_L = 10$  k $\Omega$  connected to  $V_S$  / 2,  $V_{CM} = V_S$  / 2, and  $V_{OUT} = V_S$  / 2 (unless otherwise noted)



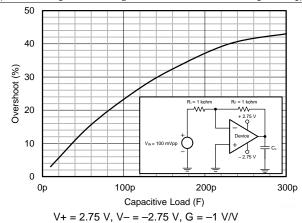
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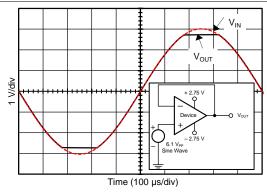
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## **Typical Characteristics (continued)**

at  $T_A = 25$  °C,  $V_S = 5.5$  V,  $R_L = 10$  k $\Omega$  connected to  $V_S$  / 2,  $V_{CM} = V_S$  / 2, and  $V_{OUT} = V_S$  / 2 (unless otherwise noted)



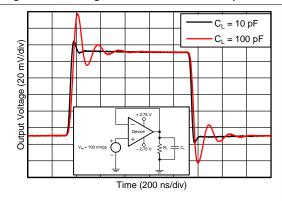


V+ = 2.75 V, V- = -2.75 V

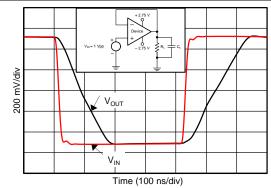
Figure 7. Small-Signal Overshoot vs Load Capacitance



Figure 8. No Phase Reversal

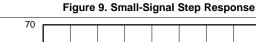


V+ = 2.75 V, V- = -2.75 V, G = 1 V/V



V+ = 2.75 V, V- = -2.75 V,  $C_L = 100 pF$ , G = 1 V/V

Figure 10. Large-Signal Step Response



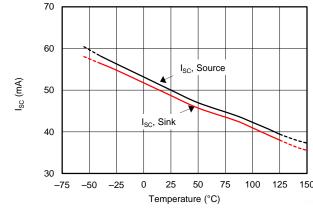


Figure 11. Short-Circuit Current vs Temperature

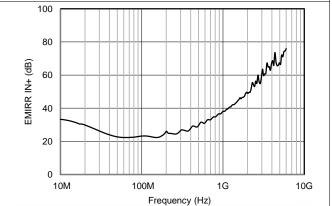


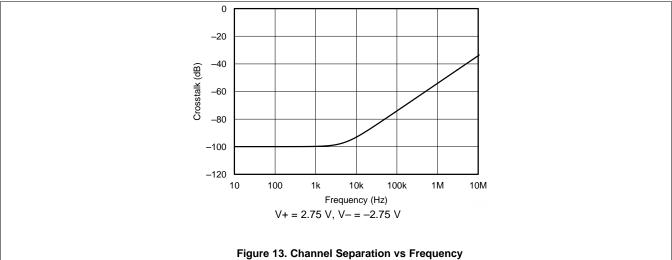
Figure 12. Electromagnetic Interference Rejection Ratio Referred to Noninverting Input vs Frequency

 $P_{RF} = -10 \text{ dBm}$ 



## **Typical Characteristics (continued)**

at  $T_A = 25$ °C,  $V_S = 5.5$  V,  $R_L = 10$  k $\Omega$  connected to  $V_S$  / 2,  $V_{CM} = V_S$  / 2, and  $V_{OUT} = V_S$  / 2 (unless otherwise noted)





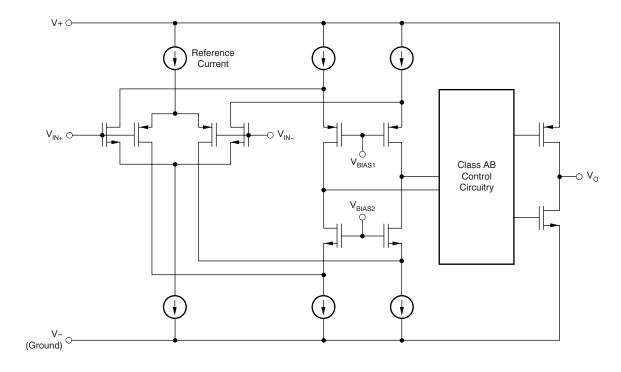
## 7 Detailed Description

#### 7.1 Overview

The TLVx316-Q1 is a family of low-power, rail-to-rail input and output operational amplifiers. These devices operate from 1.8 V to 5.5 V, are unity-gain stable, and are suitable for a wide range of general-purpose applications. The class AB output stage is capable of driving  $\leq$  10-k $\Omega$  loads connected to any point between V+ and ground. The input common-mode voltage range includes both rails and allows the TLVx316-Q1 to be used in virtually any single-supply application. Rail-to-rail input and output swing significantly increases dynamic range, especially in low-supply applications, and makes them suitable for driving sampling analog-to-digital converters (ADCs).

The TLVx316-Q1 features 10-MHz bandwidth and 6-V/ $\mu$ s slew rate with only 400- $\mu$ A supply current per channel, providing good ac performance at very-low-power consumption. DC applications are well served with a very-low input noise voltage of 12 nV/ $\sqrt{\text{Hz}}$  at 1 kHz, low input bias current (5 pA), and an input offset voltage of 0.5 mV (typical).

## 7.2 Functional Block Diagram





#### 7.3 Feature Description

#### 7.3.1 Operating Voltage

The TLVx316-Q1 operational amplifiers are fully specified and ensured for operation from 1.8 V to 5.5 V. In addition, many specifications apply from –40°C to +125°C. Parameters that vary significantly with operating voltages or temperature are illustrated in the *Typical Characteristics* section.

#### 7.3.2 Rail-to-Rail Input

The input common-mode voltage range of the TLVx316-Q1 extends 200 mV beyond the supply rails for supply voltages greater than 2.5 V. This performance is achieved with a complementary input stage: an N-channel input differential pair in parallel with a P-channel differential pair, as shown in the *Functional Block Diagram*. The N-channel pair is active for input voltages close to the positive rail, typically (V+) - 1.4 V to 200 mV above the positive supply, whereas the P-channel pair is active for inputs from 200 mV below the negative supply to approximately (V+) - 1.4 V. There is a small transition region, typically (V+) - 1.2 V to (V+) - 1 V, in which both pairs are on. This 200-mV transition region can vary up to 200 mV with process variation. Thus, the transition region (both stages on) can range from (V+) - 1.4 V to (V+) - 1.2 V on the low end, up to (V+) - 1 V to (V+) - 0.8 V on the high end. Within this transition region, PSRR, CMRR, offset voltage, offset drift, and THD can be degraded compared to device operation outside this region.

#### 7.3.3 Rail-to-Rail Output

Designed as a low-power, low-voltage operational amplifier, the TLVx316-Q1 delivers a robust output drive capability. A class AB output stage with common-source transistors is used to achieve full rail-to-rail output swing capability. For resistive loads of 10 k $\Omega$ , the output swings typically to within 30 mV of either supply rail regardless of the power-supply voltage applied. Different load conditions change the ability of the amplifier to swing close to the rails; see .

#### 7.3.4 Common-Mode Rejection Ratio (CMRR)

CMRR for the TLVx316-Q1 is specified in two ways so the best match for a given application can be selected. The *Electrical Characteristics* table provides the CMRR of the device in the common-mode range below the transition region [ $V_{CM} < (V+) - 1.4 V$ ]. This specification is the best indicator of device capability when the application requires using one of the differential input pairs. The CMRR over the entire common-mode range is specified at  $V_{CM} = -0.2 V$  to 5.7 V for  $V_S = 5.5 V$ . This last value includes the variations through the transition region.

#### 7.3.5 Capacitive Load and Stability

The TLVx316-Q1 is designed for applications where driving a capacitive load is required. As with all operational amplifiers, there may be specific instances where the TLVx316-Q1 can become unstable. The particular operational amplifier circuit configuration, layout, gain, and output loading are some of the factors to consider when establishing whether or not an amplifier is stable in operation. An operational amplifier in the unity-gain (1 V/V) buffer configuration that drives a capacitive load exhibits a greater tendency to be unstable than an amplifier operated at a higher noise gain. The capacitive load, in conjunction with the operational amplifier output resistance, creates a pole within the feedback loop that degrades the phase margin. The degradation of the phase margin increases when the capacitive loading increases. For a conservative best practice, designing for 25% overshoot (40° phase margin) provides improved stability over process variations. The equivalent series resistance (ESR) of some very-large capacitors ( $C_L$  capacitors with a value greater than 1  $\mu$ F) is sufficient to alter the phase characteristics in the feedback loop such that the amplifier remains stable. Increasing the amplifier closed-loop gain allows the amplifier to drive increasingly larger capacitance. This increased capability is evident when observing the overshoot response of the amplifier at higher voltage gains, as shown in Figure 7 (G = -1 V/V).

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### **Feature Description (continued)**

One technique for increasing the capacitive load drive capability of the amplifier operating in a unity-gain configuration is to insert a small resistor (typically  $10-\Omega$  to  $20-\Omega$ ) in series with the output, as shown in Figure 14. This resistor significantly reduces the overshoot and ringing associated with large capacitive loads. One possible problem with this technique, however, is that a voltage divider is created with the added series resistor and any resistor connected in parallel with the capacitive load. The voltage divider introduces a gain error at the output that reduces the output swing.

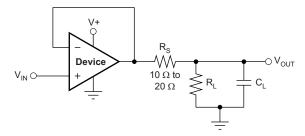


Figure 14. Improving Capacitive Load Drive

#### 7.3.6 EMI Susceptibility and Input Filtering

Operational amplifiers vary with regard to the susceptibility of the device to electromagnetic interference (EMI). If conducted EMI enters the operational amplifier, the dc offset measured at the amplifier output can shift from the nominal value when EMI is present. This shift is a result of signal rectification associated with the internal semiconductor junctions. Although EMI can affect all operational amplifier pin functions, the signal input pins are likely to be the most susceptible. The TLVx316-Q1 operational amplifier family incorporates an internal input low-pass filter that reduces the amplifier response to EMI. This filter provides both common-mode and differential-mode filtering. The filter is designed for a cutoff frequency of approximately 80 MHz (–3 dB), with a roll-off of 20 dB per decade.

The immunity of an operational amplifier can be accurately measured and quantified over a broad frequency spectrum extending from 10 MHz to 6 GHz. The EMI rejection ratio (EMIRR) metric allows operational amplifiers to be directly compared by the EMI immunity. Figure 12 illustrates the results of this testing on the TLVx316-Q1. Detailed information can be found in *EMI Rejection Ratio of Operational Amplifiers*, available for download from www.ti.com.

#### 7.3.7 Overload Recovery

Overload recovery is defined as the time required for the operational amplifier output to recover from a saturated state to a linear state. The output devices of the operational amplifier enter a saturation region when the output voltage exceeds the rated operating voltage, either because of the high input voltage or the high gain. After the device enters the saturation region, the charge carriers in the output devices require time to return back to the linear state. After the charge carriers return back to the linear state, the device begins to slew at the specified slew rate. Thus, the propagation delay in case of an overload condition is the sum of the overload recovery time and the slew time. The overload recovery time for the TLVx316-Q1 is approximately 300 ns.

#### 7.4 Device Functional Modes

The TLVx316-Q1 family has a single functional mode. These devices are powered on as long as the power-supply voltage is between 1.8 V (±0.9 V) and 5.5 V (±2.75 V).

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## 8 Application and Implementation

#### NOTE

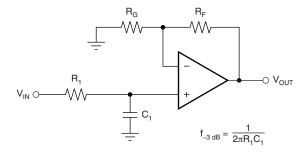
Information in the following applications sections is not part of the TI component specification, and TI does not warrant its accuracy or completeness. TI's customers are responsible for determining suitability of components for their purposes. Customers should validate and test their design implementation to confirm system functionality.

## 8.1 Application Information

The TLV316-Q1, TLV2316-Q1, and TLV4316-Q1 devices are powered on when the supply is connected. The devices can operate as a single-supply operational amplifier or a dual-supply amplifier, depending on the application.

### 8.2 System Examples

When receiving low-level signals, the device often requires limiting the bandwidth of the incoming signals into the system. The simplest way to establish this limited bandwidth is to place an RC filter at the noninverting pin of the amplifier, as shown in Figure 15.



$$\frac{V_{OUT}}{V_{IN}} = \left(1 + \frac{R_F}{R_G}\right) \left(\frac{1}{1 + sR_1C_1}\right)$$

Figure 15. Single-Pole, Low-Pass Filter

If even more attenuation is needed, the device requires a multiple-pole filter. The Sallen-Key filter can be used for this task, as shown in Figure 16. For best results, the amplifier must have a bandwidth that is eight to ten times the filter frequency bandwidth. Failure to follow this guideline can result in a phase shift of the amplifier.

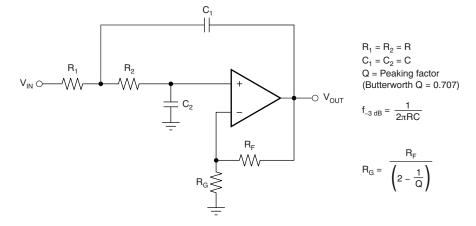


Figure 16. Two-Pole, Low-Pass, Sallen-Key Filter



## 9 Power Supply Recommendations

The TLVx316-Q1 family is specified for operation from 1.8 V to 5.5 V (±0.9 V to ±2.75 V); many specifications apply from –40°C to +125°C. The *Typical Characteristics* section presents parameters that can exhibit significant variance with regard to operating voltage or temperature.

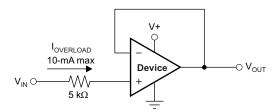
#### **CAUTION**

Supply voltages larger than 7 V can permanently damage the device; see the *Absolute Maximum Ratings* table.

Place 0.1- $\mu$ F bypass capacitors close to the power-supply pins to reduce errors coupling in from noisy or high-impedance power supplies. For more detailed information on bypass capacitor placement, see the *Layout Guidelines* section.

## 9.1 Input and ESD Protection

The TLVx316-Q1 incorporates internal ESD protection circuits on all pins. For input and output pins, this protection primarily consists of current-steering diodes connected between the input and power-supply pins. These ESD protection diodes provide in-circuit, input overdrive protection, as long as the current is limited to 10 mA, as stated in the *Absolute Maximum Ratings* table. Figure 17 shows how a series input resistor can be added to the driven input to limit the input current. The added resistor contributes thermal noise at the amplifier input and the value must be kept to a minimum in noise-sensitive applications.



**Figure 17. Input Current Protection** 

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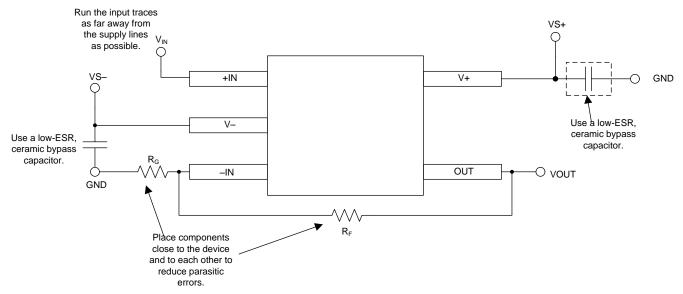
## 10 Layout

#### 10.1 Layout Guidelines

For best operational performance of the device, use good PCB layout practices, including:

- Noise can propagate into analog circuitry through the power pins of the circuit as a whole and the
  operational amplifier. Bypass capacitors reduce the coupled noise by providing low-impedance power
  sources local to the analog circuitry.
  - Connect low-ESR, 0.1-µF ceramic bypass capacitors between each supply pin and ground, placed as close to the device as possible. A single bypass capacitor from V+ to ground is applicable for singlesupply applications.
- Separate grounding for analog and digital portions of the circuitry is one of the simplest and most
  effective methods of noise suppression. One or more layers on multilayer PCBs are typically devoted to
  ground planes. A ground plane helps distribute heat and reduces EMI noise pickup. Take care to
  physically separate digital and analog grounds, paying attention to the flow of the ground current. For
  more detailed information, see Circuit Board Layout Techniques.
- To reduce parasitic coupling, run the input traces as far away from the supply or output traces as possible. If these traces cannot be kept separate, crossing the sensitive trace perpendicularly is much better than crossing in parallel with the noisy trace.
- Place the external components as close to the device as possible. Keeping R<sub>F</sub> and R<sub>G</sub> close to the inverting input minimizes parasitic capacitance, as shown in Figure 18.
- Keep the length of input traces as short as possible. Remember that the input traces are the most sensitive part of the circuit.
- Consider a driven, low-impedance guard ring around the critical traces. A guard ring can significantly reduce leakage currents from nearby traces that are at different potentials.

### 10.2 Layout Example



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Figure 18. Operational Amplifier Board Layout for a Noninverting Configuration



## 11 Device and Documentation Support

### 11.1 Documentation Support

#### 11.1.1 Related Documentation

TLVx313 Low-Power, Rail-to-Rail In/Out, 500-μV Typical Offset, 1-MHz Operational Amplifier for Cost-Sensitive Systems

TLVx314 3-MHz, Low-Power, Internal EMI Filter, RRIO, Operational Amplifier

EMI Rejection Ratio of Operational Amplifiers

QFN/SON PCB Attachment

Quad Flatpack No-Lead Logic Packages

Circuit Board Layout Techniques

Single-Ended Input to Differential Output Conversion Circuit Reference Design

#### 11.2 Related Links

Table 2 lists quick access links. Categories include technical documents, support and community resources, tools and software, and quick access to sample or buy.

Table 2. Related Links

PARTS	PRODUCT FOLDER	SAMPLE & BUY	TECHNICAL DOCUMENTS	TOOLS & SOFTWARE	SUPPORT & COMMUNITY
TLV316-Q1	Click here	Click here	Click here	Click here	Click here
TLV2316-Q1	Click here	Click here	Click here	Click here	Click here
TLV4316-Q1	Click here	Click here	Click here	Click here	Click here

#### 11.3 Community Resources

The following links connect to TI community resources. Linked contents are provided "AS IS" by the respective contributors. They do not constitute TI specifications and do not necessarily reflect TI's views; see TI's Terms of Use.

TI E2E™ Online Community TI's Engineer-to-Engineer (E2E) Community. Created to foster collaboration among engineers. At e2e.ti.com, you can ask questions, share knowledge, explore ideas and help solve problems with fellow engineers.

**Design Support** *TI's Design Support* Quickly find helpful E2E forums along with design support tools and contact information for technical support.

#### 11.4 Trademarks

E2E is a trademark of Texas Instruments.



### 11.5 Electrostatic Discharge Caution



This integrated circuit can be damaged by ESD. Texas Instruments recommends that all integrated circuits be handled with appropriate precautions. Failure to observe proper handling and installation procedures can cause damage.

ESD damage can range from subtle performance degradation to complete device failure. Precision integrated circuits may be more susceptible to damage because very small parametric changes could cause the device not to meet its published specifications.

## 11.6 Glossary

SLYZ022 — TI Glossary.

This glossary lists and explains terms, acronyms, and definitions.

## 12 Mechanical, Packaging, and Orderable Information

The following pages include mechanical, packaging, and orderable information. This information is the most current data available for the designated devices. This data is subject to change without notice and revision of this document. For browser-based versions of this data sheet, refer to the left-hand navigation.

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22-Dec-2016

#### **PACKAGING INFORMATION**

Orderable Device		Package Type	_	Pins	_		Lead/Ball Finish	MSL Peak Temp	Op Temp (°C)	Device Marking	Samples
	(1)		Drawing		Qty	(2)	(6)	(3)		(4/5)	
TLV2316QDGKRQ1	PREVIEW	VSSOP	DGK	8	2500	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	16M6	
TLV2316QDGKTQ1	PREVIEW	VSSOP	DGK	8	250	Green (RoHS & no Sb/Br)	CU NIPDAUAG	Level-2-260C-1 YEAR	-40 to 125	16M6	
TLV316QDBVRQ1	PREVIEW	SOT-23	DBV	5	3000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	16ND	
TLV316QDBVTQ1	PREVIEW	SOT-23	DBV	5	250	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	16ND	
TLV4316QPWRQ1	PREVIEW	TSSOP	PW	14	2000	Green (RoHS & no Sb/Br)	CU NIPDAU	Level-2-260C-1 YEAR	-40 to 125	V4316Q1	

(1) The marketing status values are defined as follows:

ACTIVE: Product device recommended for new designs.

LIFEBUY: TI has announced that the device will be discontinued, and a lifetime-buy period is in effect.

NRND: Not recommended for new designs. Device is in production to support existing customers, but TI does not recommend using this part in a new design.

PREVIEW: Device has been announced but is not in production. Samples may or may not be available.

**OBSOLETE:** TI has discontinued the production of the device.

(2) Eco Plan - The planned eco-friendly classification: Pb-Free (RoHS), Pb-Free (RoHS Exempt), or Green (RoHS & no Sb/Br) - please check http://www.ti.com/productcontent for the latest availability information and additional product content details.

**TBD:** The Pb-Free/Green conversion plan has not been defined.

**Pb-Free** (RoHS): TI's terms "Lead-Free" or "Pb-Free" mean semiconductor products that are compatible with the current RoHS requirements for all 6 substances, including the requirement that lead not exceed 0.1% by weight in homogeneous materials. Where designed to be soldered at high temperatures, TI Pb-Free products are suitable for use in specified lead-free processes. **Pb-Free** (RoHS Exempt): This component has a RoHS exemption for either 1) lead-based flip-chip solder bumps used between the die and package, or 2) lead-based die adhesive used between the die and leadframe. The component is otherwise considered Pb-Free (RoHS compatible) as defined above.

Green (RoHS & no Sb/Br): TI defines "Green" to mean Pb-Free (RoHS compatible), and free of Bromine (Br) and Antimony (Sb) based flame retardants (Br or Sb do not exceed 0.1% by weight in homogeneous material)

<sup>(3)</sup> MSL, Peak Temp. - The Moisture Sensitivity Level rating according to the JEDEC industry standard classifications, and peak solder temperature.

<sup>(4)</sup> There may be additional marking, which relates to the logo, the lot trace code information, or the environmental category on the device.

<sup>(5)</sup> Multiple Device Markings will be inside parentheses. Only one Device Marking contained in parentheses and separated by a "~" will appear on a device. If a line is indented then it is a continuation of the previous line and the two combined represent the entire Device Marking for that device.



## PACKAGE OPTION ADDENDUM

22-Dec-2016

(6) Lead/Ball Finish - Orderable Devices may have multiple material finish options. Finish options are separated by a vertical ruled line. Lead/Ball Finish values may wrap to two lines if the finish value exceeds the maximum column width.

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#### OTHER QUALIFIED VERSIONS OF TLV2316-Q1, TLV316-Q1, TLV4316-Q1:

Catalog: TLV2316, TLV316, TLV4316

NOTE: Qualified Version Definitions:

Catalog - TI's standard catalog product

## **PACKAGE MATERIALS INFORMATION**

www.ti.com 23-Dec-2016

## TAPE AND REEL INFORMATION





Α0	Dimension designed to accommodate the component width
	Dimension designed to accommodate the component length
K0	Dimension designed to accommodate the component thickness
	Overall width of the carrier tape
P1	Pitch between successive cavity centers

### QUADRANT ASSIGNMENTS FOR PIN 1 ORIENTATION IN TAPE



#### \*All dimensions are nominal

Device	Package Type	Package Drawing		SPQ	Reel Diameter (mm)	Reel Width W1 (mm)	A0 (mm)	B0 (mm)	K0 (mm)	P1 (mm)	W (mm)	Pin1 Quadrant
TLV2316QDGKRQ1	VSSOP	DGK	8	2500	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV2316QDGKTQ1	VSSOP	DGK	8	250	330.0	12.4	5.3	3.4	1.4	8.0	12.0	Q1
TLV316QDBVRQ1	SOT-23	DBV	5	3000	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3
TLV316QDBVTQ1	SOT-23	DBV	5	250	178.0	9.0	3.3	3.2	1.4	4.0	8.0	Q3

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\*All dimensions are nominal

Device	Package Type Package Drawing F		Pins	SPQ	Length (mm)	Width (mm)	Height (mm)
TLV2316QDGKRQ1	VSSOP	DGK	8	2500	366.0	364.0	50.0
TLV2316QDGKTQ1	VSSOP	DGK	8	250	366.0	364.0	50.0
TLV316QDBVRQ1	SOT-23	DBV	5	3000	180.0	180.0	18.0
TLV316QDBVTQ1	SOT-23	DBV	5	250	180.0	180.0	18.0

PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters. Dimensioning and tolerancing per ASME Y14.5M—1994.
- B. This drawing is subject to change without notice.
  - Sody length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0,15 each side.
- Body width does not include interlead flash. Interlead flash shall not exceed 0,25 each side.
- E. Falls within JEDEC MO-153



# PW (R-PDSO-G14)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



DBV (R-PDSO-G5)

## PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Body dimensions do not include mold flash or protrusion. Mold flash and protrusion shall not exceed 0.15 per side.
- D. Falls within JEDEC MO-178 Variation AA.



# DBV (R-PDSO-G5)

## PLASTIC SMALL OUTLINE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Customers should place a note on the circuit board fabrication drawing not to alter the center solder mask defined pad.
- D. Publication IPC-7351 is recommended for alternate designs.
- E. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Example stencil design based on a 50% volumetric metal load solder paste. Refer to IPC-7525 for other stencil recommendations.



# DGK (S-PDSO-G8)

# PLASTIC SMALL-OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- Body length does not include mold flash, protrusions, or gate burrs. Mold flash, protrusions, or gate burrs shall not exceed 0.15 per end.
- Body width does not include interlead flash. Interlead flash shall not exceed 0.50 per side.
- E. Falls within JEDEC MO-187 variation AA, except interlead flash.



# DGK (S-PDSO-G8)

## PLASTIC SMALL OUTLINE PACKAGE



- A. All linear dimensions are in millimeters.
- B. This drawing is subject to change without notice.
- C. Publication IPC-7351 is recommended for alternate designs.
- D. Laser cutting apertures with trapezoidal walls and also rounding corners will offer better paste release. Customers should contact their board assembly site for stencil design recommendations. Refer to IPC-7525 for other stencil recommendations.
- E. Customers should contact their board fabrication site for solder mask tolerances between and around signal pads.



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